CSCI E-82a Probabilistic Programming and Al Lecture 4 Learning for Graphical Models

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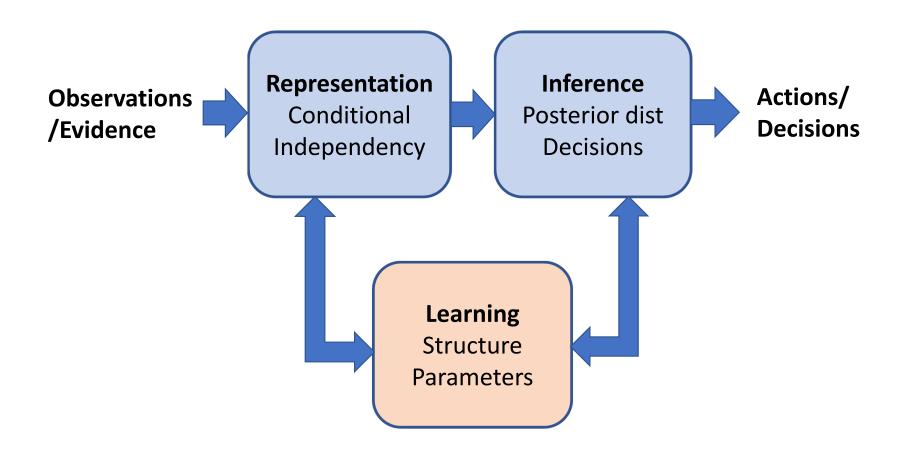
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Outline

- Learning for Graphical Models
- Introduction to Learning Model Parameters
 - The Binomial and Beta Distributions
 - The Kullback-Leibler Divergence
 - Maximum Likelihood for the Binomial Distribution
 - Bayesian Estimation for Binomial Distribution
 - Categorical and Dirichlet Distributions
 - Working with Multivariate Distributions
- Learning Model Structure
 - Learning structure of DAGs
 - Mutual Information for K2 Scoring
 - Chow-Liu Tree Algorithm

Learning can involve estimating model parameters or finding structure

- Estimating model parameters is relatively easy
 - Requires minimal data
 - Learning can be incremental
- Learning structure is very difficult
 - Is unsupervised learning
 - Potentially requires massive amounts of data
 - Exhaustive methods are NP complete!



In the first 2 lessons we focused on representation

- Representation allows us to define or represent a model
- We have investigated two representations:
 - Bayes networks or directed acyclic graphs (DAGs)
 - Undirected graphical networks, Markov random fields (MRF)
- Efficient representation
 - Factor distributions
 - Represent independences
- A good representation is required to perform inference

In the last lesson our focus was on inference

- Inference is the process of getting useful results from graphical models
 - Posterior distributions
 - MAP
- Exact inference algorithms include:
 - Variable elimination
 - Belief propagation
 - Junction-tree algorithm

Part 1 Learning Model Parameters



Introduction to Learning Model Parameters

Two classes of learning methods

- Frequentist method
 - Need only likelihood function
 - Find parameters for maximum likelihood (ML)
- Bayesian learning
 - Requires **prior distribution** and likelihood function
 - Can compute posterior distribution or maximum a postiori (MAP)
 - Learn incrementally when new observations are available

Models for binary variables in {0,1}

- Single realization, {0,1} == {failure, success}
- Bernoulli distribution models probability of success, Θ , for single trial:

$$p(v = 1) = \Theta$$

where:

v = an observation

 $\Theta = probability parameter$

• Bernoulli distribution is a **parametric distribution** with a single parameter

Models for binary variables in {0,1}

- How do we model distribution of multiple trials
- **Binomial distribution** determines the probability of k successes in n trials, given a parameter Θ

$$p(v = k \mid \Theta) = \binom{n}{k} \Theta^k (1 - \Theta)^{n-k}$$

Where, $\binom{n}{k}$ is the **binomial coefficient**, spoken as n choose k

How can we express the **likelihood** for the trials with binary outcomes?

• Use the **Beta distribution**:

$$p(x \mid \alpha, \beta) = \frac{1}{B(\alpha, \beta)} x^{\alpha - 1} (1 - x)^{\beta - 1}, \ 0 \le x \le 1$$

Where the **Beta function** is,

$$B(\alpha, \beta) = \frac{\Gamma(\alpha)\Gamma(\beta)}{\Gamma(\alpha, \beta)}$$

and, $\Gamma(x)$ is the Gamma function

The Beta distribution looks complicated!

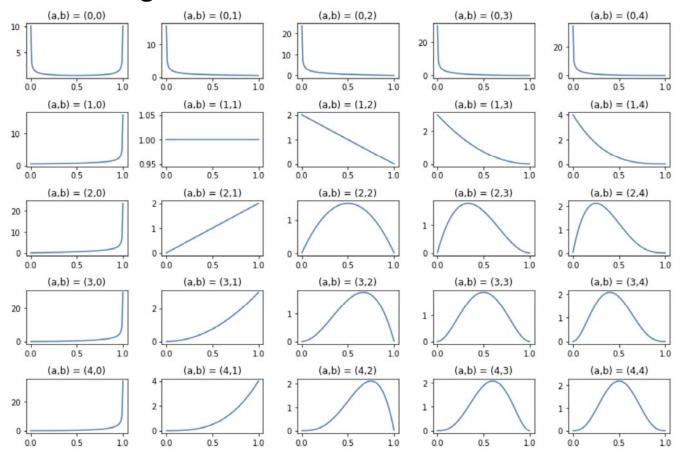
How can we interpret the Beta distribution?

$$p(x \mid \alpha, \beta) = \frac{1}{B(\alpha, \beta)} x^{\alpha - 1} (1 - x)^{\beta - 1}, \ 0 \le x \le 1$$

- Simple interpretation, α and β are counts:
 - α are counts of successes
 - β are counts of failures
 - Higher counts given narrower distribution
 - If $\alpha = \beta$, is symmetric
 - Beta distribution defined on the interval (0,1)

How to interpret the Beta distribution

Distribution changes with counts



Estimation of Distribution Parameters

How can best find the parameters of a distribution?

- Two possible approaches
 - Give same results in limit of large dataset
- Maximum likelihood finds model parameter that maximizes likelihood of distribution
 - Can use the Kullback-Leibler (KL) divergence between the estimated distribution and the data – information theoretic approach
 - Can find root of likelihood function by taking derivatives
- Use Bayesian estimation to find MAP or posterior distribution of parameter
 - Must specify a prior distribution

How can we measure the fit of a likelihood function?

- One possibility is the Kullback-Leibler (KL) divergence between an estimated distribution and the actual distribution
 - Information theoretic approach
- Start with **Shannon entropy**:

$$\mathbb{H}(I) = E[I(X)] = E[-ln_b(P(X))] = -\sum_{i=1}^{n} P(x_i)ln_b(P(x_i))$$

- Shannon entropy measures the information content of a probability distribution
- But we need to compare two distributions

How can we measure the fit of a likelihood function?

• The K-L divergence is between two distributions p(x) and q(x) is defined:

$$\mathbb{D}_{KL}(P \parallel Q) = -\sum_{i=1}^{n} p(x_i) \ln_b \frac{p(x_i)}{q(x_i)}$$

- The K-L divergence is 0 if p(x) = q(x)
- K-L divergence increases the more p(x) differs from q(x)
- But, K-L divergence is **not symmetric**

How can we measure the fit of a likelihood function?

• The **cross entropy** is defined:

$$\mathbb{H}(P,Q) = -\sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

We can then rewrite the K-L divergence as:

$$\mathbb{D}_{KL}(P \parallel Q) = \sum_{i=1}^{n} p(x_i) \ln_b p(x_i) - \sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

$$\mathbb{D}_{KL}(P \parallel Q) = \mathbb{H}(P) + \mathbb{H}(P, Q)$$

$$\mathbb{D}_{KL}(P \parallel Q) = Entropy(P) + Cross\ Entropy(P, Q)$$

How can we measure the fit of a likelihood function?

Start with the expansion of the K-L divergence:

$$\mathbb{D}_{KL}(P \parallel Q) = \sum_{i=1}^{n} p(x_i) \ln_b p(x_i) - \sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

$$\mathbb{D}_{KL}(P \parallel Q) = \mathbb{H}(P) + \mathbb{H}(P, Q)$$

- When comparing distributions, $\mathbb{H}(P)$ is constant for any reference distribution p(x)
- We only need to deal with $\mathbb{H}(P,Q)$ to compare the two distributions

How can we measure the fit of a likelihood function?

• We only need to deal with $\mathbb{H}(P,Q)$ to compare the two distributions

$$\mathbb{H}(P,Q) = -\sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

- The problem is, we never will know p(x)
- So how can we compute p(x)?
- We can use an approximation:

$$\mathbb{H}(P,Q) = -\frac{1}{N} \sum_{i=1}^{n} ln_b q(x_i)$$

Maximum likelihood with K-L divergence

• For a generating distribution $p^*(x)$ we can write the K-L divergence with the approximation q(x):

$$\mathbb{D}_{KL}(p^* \parallel q) = \sum_{i=1}^n p^*(x_i) \ln_b \frac{p^*(x_i)}{q(x_i)} = -\mathbb{H}(p^*) - \mathbb{E}_{x \sim p^*}[\log q(x)]$$

- The first term only depends on p* and does not depend on q(x)
- We want to minimize K-L divergence, so maximize $\mathbb{E}_{x \sim p^*}[log \ q(x)]$
- But, the expectation requires generating data from p*
- Complication: we will never know p*!

Maximum likelihood with K-L divergence

- Complication: we will never know p*!
- We can use a Monte Carlo like approximation:

$$\mathbb{E}_{x \sim p^*}[log \ q(x)] = \frac{1}{|D|} \sum_{x \in D} log \ q(x)$$

Where D is the dataset drawn from the distribution p*

The maximum likelihood can be expressed:

$$\max_{p \in D} \frac{1}{|D|} \sum_{x \in D} \log q(x)$$

• This approximation minimizes K-L divergence!

Maximum Likelihood for the Binomial Distribution

Maximum likelihood for model parameter Θ

- How can we apply the maximum likelihood method to find the parameter of the Binomial distribution?
- Start with the likelihood function $\mathcal{L}(\Theta, \mathcal{V}) = p(\mathcal{V} \mid \Theta)$
- Using the log likelihood we wish to find Θ such that:

$$\hat{\Theta} \doteq argmax_{\Theta} \{ log(p(\mathcal{V} \mid \Theta)) \}$$

Maximum Likelihood for the Binomial Distribution

Maximum likelihood for model parameter Θ

For the Binomial distribution the likelihood is:

$$L(\Theta) = \prod_{i=1}^{n} \Theta^{\nu_i} (1 - \Theta)^{(1-\nu_i)}$$

Where v is the data vector

• The log-likelihood is then:

$$\log(L(\Theta)) = \log(\Theta) \sum_{i=1}^{n} v_i + \log(1 - \Theta) \sum_{i=1}^{n} (1 - v_i)$$

Maximum Likelihood for the Binomial Distribution

Maximum likelihood for model parameter Θ

Setting the derivative of the log-likelihood to 0:

$$\frac{\partial l(\Theta)}{\partial \Theta} = \frac{\sum_{i=1}^{n} \nu_i}{\Theta} - \frac{\sum_{i=1}^{n} (1 - \nu_i)}{1 - \Theta} = 0$$

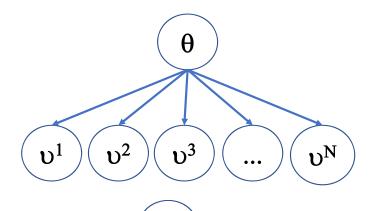
• With solution:

$$\Theta = \frac{1}{n} \sum_{i=1}^{n} \nu_i$$

• Or in simple terms:

$$\Theta = \frac{count\ of\ successes}{total\ count}$$

How to perform Bayesian estimation on the model parameter Θ ?



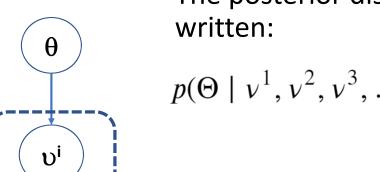
Start with a vector of observations

$$\vec{v} = \{v^1, v^2, v^3, \dots v^N\}$$

• We can represent the generating distribution as a directed graphical model with parameter $\boldsymbol{\theta}$

• Or, summarize with plate notation

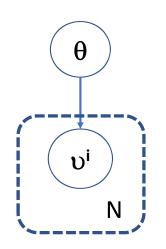
How to perform Bayesian estimation on the model parameter Θ ?



• The posterior distribution of Θ given the data vector $\vec{\mathcal{V}}$ can be written:

$$\begin{split} p(\Theta \mid v^1, v^2, v^3, \dots v^N) &\propto p(\Theta) \prod_{n=1}^N p(v^n \mid \Theta) \\ &\propto p(\Theta) \prod_{n=1}^N \Theta^{I(v^n=1)} (1 - \Theta)^{I(v^n=0)} \\ &\propto p(\Theta) \; \Theta^{\sum_{n=1}^N I(v^n=1)} (1 - \Theta)^{\sum_{n=1}^N I(v^n=0)} \end{split}$$

How to perform Bayesian estimation on the model parameter Θ ?



• Now, define the binary result {True, False}, we can define the posterior distribution of Θ :

$$p(\Theta \mid v^1, v^2, v^3, \dots v^N) \propto p(\Theta) \Theta^{N_T} (1 - \Theta)^{N_F}$$

• Or, given a count operator C we can write the likelihood as:

$$\Theta^{C(v_i=1)}(1-\Theta)^{C(v_i=0)}$$

• But how do we express the prior distribution $P(\Theta)$?

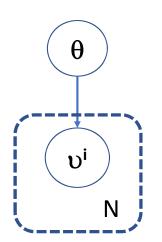
How to perform Bayesian estimation on the model parameter Θ ?

- How do we express the prior distribution $P(\Theta)$?
- Recall, the Beta distribution is the **conjugate** of the Binomial distribution and has the form:

$$p(x \mid \alpha, \beta) = \frac{1}{B(\alpha, \beta)} x^{\alpha - 1} (1 - x)^{\beta - 1}$$

- The product of a distribution and its conjugate has the same family as the distribution
- Define a prior using **pseudo counts**
- ullet Set the parameter lpha to the number of 'prior successes'
- Set the parameter β to the number of 'prior failures'

How to perform Bayesian estimation on the model parameter Θ ?



- How do we express the prior distribution $P(\Theta)$?
- Using the pseudo counts for the prior, the posterior of q becomes:

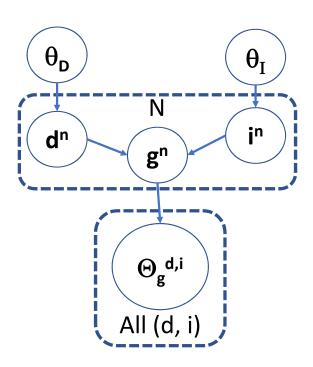
$$p(\Theta \mid v^1, v^2, v^3, \dots v^N) \propto \Theta^{\left(\sum_{n=1}^N I(v^n=1)\right) + \alpha} (1-\Theta)^{\left(\sum_{n=1}^N I(v^n=0)\right) + \beta}$$

• And, the **Maximum A Posteriori (MAP)** value of θ is:

$$\Theta = \frac{count \ of \ successes + \alpha}{total \ count + \alpha + \beta}$$

Properties of the prior distribution of Θ given pseudo counts

- The higher the ratio α/β the larger the prior value of Θ
- The larger the sum of α and β the stronger the prior. Small values of α and β specify a vague prior
- ullet The larger the actual counts, the less important the prior in determining ullet
- If $\alpha=\beta=0$ the Bayesian estimate of Θ is identical to the maximum likelihood estimate
- If there are no actual counts, the MAP estimate of Θ is the prior
- The prior regularizes the estimation of Θ , even for variables with no observations



How can we work with problems with multiple categories?

- Use the categorical distribution for multi-category variables
 - Sometimes called (incorrectly) the multinomial distribution
 - k category distribution parameterized by k probabilities
 - Is the multi-class generalization fo the Binomial distribution
- The Dirichlet distribution is the conjugate of the categorical distribution
 - Is the multi-class extension of the Beta distribution

How can we work with problems with multiple categories?

• The categorical distribution, where x is in the ith category, is expressed:

$$f(x = i \mid p) = p_i$$

Where for k categories have probabilities:

$$p = (p_1, \ldots, p_k)$$

and with the constraint,

$$\sum_{i=1}^{k} p_i = 1.0$$

How can we work with problems with multiple categories?

Use Iverson bracket notation:

$$[x = i] = 1$$
 or 0 otherwise

• This notation gives a compact way to write the categorical distribution:

$$f(x = i \mid p) = \prod_{i=1}^{k} p_i^{[x=i]}$$

How can we work with problems with multiple categories?

- What is the maximum likelihood estimate (MLE) of the probability of each of the k categories, $p=(p_1,\ldots,p_k)$?
- Given the counts for each of the categories, $X = (c_1, c_2, \dots, c_n)$, the MLE is:

$$E(p_i \mid \mathcal{X}) = \frac{c_i}{N}$$

• The above is a generalization of the MLE for the Binomial distribution

The Dirichlet distribution is the conjugate of the categorical

- Dirichlet distribution is the generalization of the Beta distribution for multiple categories
- For n categories x_1, x_2, \ldots, x_n , and **concentration parameters** $\alpha_1, \alpha_2, \ldots, \alpha_n$
- Concentration parameters specify how concentrated the distribution is for each category
- Express the Dirichlet distribution:

$$f(x_1, x_2, \dots, x_n; \alpha_1, \alpha_2, \dots, \alpha_n) = \frac{1}{B(\alpha)} \prod_{i=1}^n x_i^{\alpha_i - 1}$$

Categorical and Dirichlet Distributions

The Dirichlet distribution is the conjugate of the categorical

• Express the Dirichlet distribution:

$$f(x_1, x_2, \dots, x_n; \alpha_1, \alpha_2, \dots, \alpha_n) = \frac{1}{B(\alpha)} \prod_{i=1}^n x_i^{\alpha_i - 1}$$

Where the Beta function in terms of gamma (Γ) functions is;

$$B(\alpha) = \frac{\prod_{i=1}^{n} \Gamma(\alpha_i)}{\sum_{i=1}^{n} \Gamma(\alpha_i)}$$

And with constraints,

$$\sum_{i=1}^{n} x_i = 1$$
$$x_i \ge 0$$

Categorical and Dirichlet Distributions

How can we work with problems with multiple categories?

- The probability parameters of the categorical distribution for each category, $p=(p_1,\ldots,p_k)$
- Bayesian MAP estimate of the parameters of the categorical distribution given the counts for each category $X = (c_1, c_2, \dots, c_n)$

$$E(p_i \mid X, \boldsymbol{\alpha}) = \frac{c_i + \alpha_i}{N + \sum_k \alpha_k}$$

 Is a generalization of the expression for Binomially distributed results with Beta prior

Categorical and Dirichlet Distributions

How can we work with problems with multiple categories?

- Concentration parameters specify how concentrated the distribution is for each category
- The concentration pseudocounts parameters specify the prior Dirichlet distribution:
 - Categories with larger pseudocounts have higher prior probabilities
 - The ratio of the total sum of pseudocounts to the total number of actual counts expresses the strength of the prior. A larger ratio is a stronger prior
 - When all α_i are equal the prior is uniform
 - For a relatively large number or actual counts the prior has less influence and the estimates approach the MLE.

Working with Multivariate Distributions

How do we estimate the parameter vector, Θ ?

- Up to now, we have only considered single parameter models
- How can we perform parameter estimation for multivariable distributions?
- Consider the joint distribution of the grade, G, the difficulty of the course, D, and the intelligence of the student, I, from the student job example:

$$p(\Theta_D, \Theta_I, \Theta_G)$$

- Three parameters, $\Theta_D, \Theta_I, \Theta_G$, must be estimated simultaneously
- Simplify this process by the global independence assumption
- The global independence assumption decouples the estimation of the parameter

Working with Multivariate Distributions

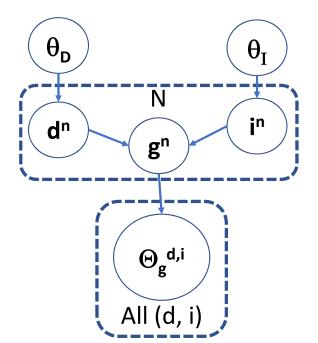
How do we estimate the parameter vector, Θ ?

 With the global independence assumption, fit the parameters for of the factorized distribution:

$$p(\Theta_D, \Theta_I, \Theta_G) = p(\Theta_D)p(\Theta_I)p(\Theta_G)$$

• Use the N data samples, $X = (c_1, c_2, \dots, c_n)$

Working with Multivariate Distributions



How do we estimate the parameter vector, $\mathbf{\Theta}$?

For factorized distribution:

$$p(\Theta_D, \Theta_I, \Theta_G) = p(\Theta_D)p(\Theta_I)p(\Theta_G)$$

- Use plate notation to show model for estimation from N samples
- If all samples are iid the factorization represented by the Dag becomes:

$$p(\Theta_D, \Theta_I, \Theta_G) = p(\Theta_D)p(\Theta_I)p(\Theta_G) \prod_{n=1}^N p(d^n \mid \Theta_D)p(i^n \mid \Theta_I)p(g^n \mid d^n, i^n, \Theta_G)$$

 In summary, we can fit the model by independently maximizing the likelihood

Part 2 Learning Model Structure



Methods to find the structure of a DAG?

- Focus on learning structure of DAGs from data
- Learn structure from data?
- Use expert opinion?
- Combination of both?

How do we find the structure of a DAG?

- Expert opinion is both useful and problematic
 - Involves subjective judgement
 - May not have agreement between experts
 - Hard for complex problems
- Expert option may provide useful constraint or prior

How do we find the structure of a DAG?

- Is an unsupervised learning problem
 - Used as a data mining method
 - No marked cases
 - Results hard to evaluate
- Typically, requires massive amounts of data
- Significant bias-variance trade-off
 - Model with high complexity or low bias is overfit with high variance
 - Model with low complexity or high bias is underfit with low variance

How do we find the structure of a DAG?

- Algorithms have two components
- Define the score metric
 - Score metric must reflect trade-off between fit (low variance) and complexity
 - Likelihood based score
 - Bayesian score
 - Information theortic
- A search problem looking for the optimal score
 - Search for a good solution is a classic AI problem

How can we score a model?

- Score metric must reflect trade-off between fit (low variance) and complexity
- Given a graph, \mathcal{G} , and data D a general likelihood formulation is:

$$Score(\mathcal{G}:D) = log(\mathcal{L}(\mathcal{G}:D)) - \phi(n) \parallel \mathcal{G} \parallel$$

• Where,

 $\mathcal{L}(\mathcal{G}:D) = likelihood given the fitted graph parameters$ $<math>\|\mathcal{G}\| = number \ of \ parameters \ in \ \mathcal{G}$, a measure of complexity $n = number \ of \ samples$

 $\phi(n)$ = a function to adjust complexity for the amount of data

How can we score a model?

 Score metric must reflect trade-off between fit (low variance) and complexity

$$Score(\mathcal{G}:D) = log(\mathcal{L}(\mathcal{G}:D)) - \phi(n) \parallel \mathcal{G} \parallel$$

- Maximizing the first term, $log(\mathcal{L}(\mathcal{G}:D))$, minimizes bias, but increases variance
- The second term, $-\phi(n)\parallel\mathcal{G}\parallel$, penalizes variance at the expense of bias

How can we score a model?

- The Bayesian Information Criteria, BIC, is one such metric
- Also know as Schwartz Information Criteria
- BIC is related to the Akaki Information Criteria, AIC
- Given a graph, G, and data D the BIC is:

$$BIC = ln(n) \parallel G \parallel -2 ln(\mathcal{L}(\mathcal{G} : D))$$

Where,

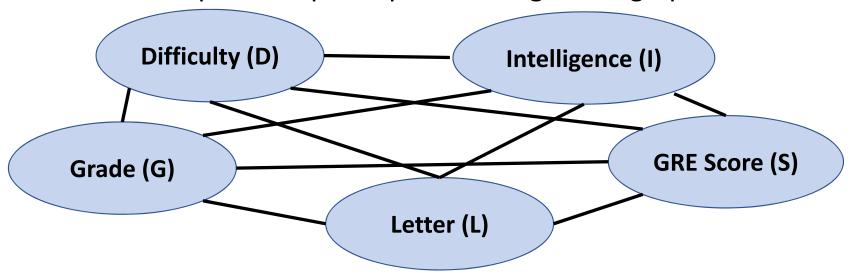
 $\mathcal{L}(\mathcal{G}:D) = likelihood\ given\ the\ fitted\ graph\ parameters$ $\|\mathcal{G}\| = number\ of\ parameters\ in\ \mathcal{G}$, a measure of complexity $\phi(n) = ln(\phi) = adjust\ complexity\ for\ the\ amount\ of\ data$

How can we score a model?

- Properties of the Bayesian Information Criteria, BIC:
- The higher the likelihood, the lower the BIC
- Models with lower BIC are considered better
- Models with more parameters have higher BIC
- BIC penalizes complex models and prefers simple models with few edges
- But, name is misleading; Despite the name, this is not a Bayesian method!
 - No prior
 - Computes a score, not a probability

How to perform the search to optimize the model score

Consider a simple example of possible edges in a graph



• Exhaustive search across all possible n edges is computationally prohibitive:

$$C(n) = n^{O(2^{O(n)})}$$

- Exhaustive search is not an option, so what can we do?
- Apply search heuristics!
- Al researchers have worked on search heuristics for decades
 - For a comprehensive discussion of search heuristics for AI see chapters
 3 and 4 of Russell and Norvig, third edition
- Examples of search heuristics used for finding DAG structure
 - Hill climbing search
 - Taboo search
- Search can work in two possible starting points:
 - A fully connected network, wherein edges are removed
 - Competly unconnected network, wherein edges are added

- Hill climb search is a greedy search algorithm for discrete valued problems
 - Not to be confused with gradient ascent/descent for continuous valued problems
 - Both are locally greedy search methods
- Proceeds through a series of discrete states to find the optimal or terminal state
- Next state found by a single addition or removal of edge local search
- Search continues until the improvement in the objective function is less than some threshold

- Hill climb search is a greedy search algorithm and can become stuck at a local optimum
 - Multiple random starts help better explore the state (solution) space
 - Using a taboo list of last N steps limits backtracking and encourages exploration of space
- Commonly used improvements to the basic algorithm include:
 - Closest state which improves the objective function is taken as the next step
 - Successor state with the largest possible improvement is taken at each step

- Taboo search was developed in the 1980s
- Keeps a global taboo list of states already visited to prevent wasted search cycles
- Can take random exploration steps if no local improvement found
- Often faster than hill climbing
- But taboo list can use too much memory for larger problems

The K2 score and K2 algorithm are a Bayesian approach

- The K2 algorithm uses locally greedy search; e.g. hill climbing
- Steps of the K2 algorithm:
 - Node order that search follows is determined
 - 2. Begin search with first node in the order; initially has no parents
 - 3. Add parents incrementally in order that maximizes score increase
 - 4. The search terminates when the score no longer increases
- K2 algorithm requires no constraint on the number of parents

The K2 score and K2 algorithm are a Bayesian approach

- Success of K2 algorithm is dependent on node ordering
- Poor ordering leads to poor results
- Random starts on determining the ordering can improve results
- See paper by Learner and Malka for complete details: http://www.ee.bgu.ac.il/~boaz/LernerMalkaAAI2011.pdf

The K2 score and K2 algorithm are a Bayesian approach

- Need a score method for the K2 algorithm
- For a graph, G, with n nodes and data, D, sampled from the joint distribution, the Bayesian score is:

$$p(D \mid \mathcal{G}) = \frac{p(\mathcal{G} \mid D)p(\mathcal{G})}{p(D)} = \frac{p(\mathcal{G}, D)}{p(D)}$$

• The prior distribution, p(G), is typically uniform Dirichlet

The K2 score and K2 algorithm are a Bayesian approach

- ullet Since the data is the same for every model, p(D), is the same
- Assuming the parameters associated with each variable are independent gives the decomposition:

$$p(\mathcal{G}, D) = p(\mathcal{G}) \prod_{i=1}^{n} g(d_i, \mathbf{P_{a_i}})$$

Where, $g(d_i, \mathbf{P_{a_i}})$ is the subscore for the i^{th} dimension

Allows the algorithm work locally, variable by variable

Start by defining **Shannon Entropy**?

$$\mathbb{H}(I) = E[I(X)]$$

Where: E[X] = the expectation of X.

I(X) = the information content of X.

But, we work with probability distributions, so:

$$\mathbb{H}(I) = E[-ln_b(P(X))] = -\sum_{i=1}^{n} P(x_i) ln_b(P(x_i))$$

Where: P(X) = probability of X.

b =base of the logarithm.

- We need to measure the difference between the distribution of our approximation and the distribution of the data
- The Kullback-Leibler divergence between two distributions P(X) and Q(X) is such a measure:

$$\mathbb{D}_{KL}(P \parallel Q) = -\sum_{i=1}^{n} p(x_i) \ln_b \frac{p(x_i)}{q(x_i)}$$

- How do we compute KL divergence?
- If we knew P(X) we would not need to compute KL divergence
- We can expand KL divergence as:

$$\mathbb{D}_{KL}(P \parallel Q) = \sum_{i=1}^{n} p(x_i) \ln_b p(x_i) - \sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

$$\mathbb{D}_{KL}(P \parallel Q) = \mathbb{H}(P) + \mathbb{H}(P, Q)$$

$$\mathbb{D}_{KL}(P \parallel Q) = Entropy(P) + Cross\ Entropy(P, Q)$$

Given: $\mathbb{D}_{KL}(P \parallel Q) = \mathbb{H}(P) + \mathbb{H}(P,Q)$

The term $\mathbb{H}(P)$ is constant

So, we only need the **cross entropy** term:

$$\mathbb{H}(P,Q) = -\sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

How can we compute cross entropy when we don't know P(X):

$$\mathbb{H}(P,Q) = -\sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

Since we don't know P(X), use the approximation:

$$\mathbb{H}(P,Q) = -\frac{1}{N} \sum_{i=1}^{n} ln_b q(x_i)$$

Mutual Information for K2 Scoring

The K2 score is based on mutual information

Mutual information is defined:

$$I(X;Y) = \sum_{y \in Y} \sum_{x \in X} p(x,y) log\left(\frac{p(x,y)}{p(x)p(y)}\right)$$

If the two distributions are identical then:

$$log\left(\frac{p(x,y)}{p(x)p(y)}\right) = log(1) = 0$$

- In words, there is no mutual information between identical distributions
- Mutual information is always greater than 0; $I(X;Y) \ge 0$
- Mutual information is **symmetric**; I(X;Y) = I(Y;X)

Mutual Information for K2 Scoring

The K2 score is based on mutual information

Relate mutual information to entropy and conditional entropy:

$$I(X;Y) \equiv H(X) - H(X \mid Y) \equiv H(Y) - H(Y \mid X)$$

$$\equiv H(X) + H(Y) - H(X,Y)$$

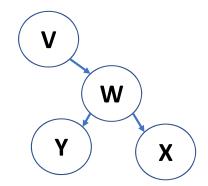
 Can also relate mutual information to the KL divergence between the joint distribution and the product of the distributions of the variables

$$I(X;Y) = D_{KL} \left(p(x,y) \parallel p(x) p(y) \right)$$

 In words, the mutual information between two variables is 0 if the variables are independent

Use information theory to find node order

- Chow-Li tree algorithm uses information theory to find a tree structure graph with a factorized distribution that best fits the data distribution
- But, this problem is highly under-constrained!
- In first order tree structure graph a node can only have one parent:



First Order Tree

Use information theory to find node order

- Express K-L divergence and mutual information using using expectation over a distribution, $\mathbb E$
- K-L divergence, given data *D*:

$$KL(p \parallel q) = \mathbb{E}_{p(x)} \left(log(p(x)) \right) - \sum_{i=1}^{D} \mathbb{E}_{p(x_i, x_{pa(i)})} \left(log(q(x_i \mid x_{pa(i)})) \right)$$

• And, mutual information (MI) for two variables, xi, xj:

$$MI(x_i, x_j) = \mathbb{E}_{p(x)} \left(log \left(\frac{p(x_i, p_j)}{p(x_i) p(x_j)} \right) \right)$$

• Thus, K-L divergence can be formulated in terms of MI:

$$KL(p \parallel q) = -\sum_{i=1}^{D} MI(x_i; x_{pa(i)}) - \mathbb{E}_{p(x_i)} \left(log(p(x_i)) \right) + Constant$$

Use information theory to find node order

K-L divergence in terms of MI:

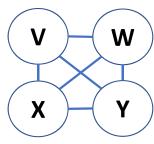
$$KL(p \parallel q) = -\sum_{i=1}^{D} MI(x_i; x_{pa(i)}) - \mathbb{E}_{p(x_i)} \left(log(p(x_i))\right) + Constant$$

- The second term depends only on $p(x_i)$, and third term is constant
- So, minimizing the K-L divergence is the same as maximizing the sum of MI with respect to the parents

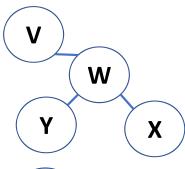
$$\sum_{i=1}^{D} MI(x_i; x_{pa(i)})$$

 But for any finite data set the MI is unlikely to be exactly 0, so must constrain problem to first order tree

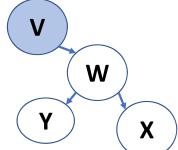
Steps of the Chow-Lui algorithm



1. Compute the MI for all edges in fully connected network



2. Compute the **maximal weight spanning tree** that connects are vertices; this is a hard problem by itself!



3. Pick an arbitrary **root** and assign directions to the arrows radiating out from the root

Vocabulary

• The K-L divergence is between two distributions p(x) and q(x) is defined:

$$\mathbb{D}_{KL}(P \parallel Q) = -\sum_{i=1}^{n} p(x_i) \ln_b \frac{p(x_i)}{q(x_i)}$$

• The **cross entropy** is defined:

$$\mathbb{H}(P,Q) = -\sum_{i=1}^{n} p(x_i) \ln_b q(x_i)$$

• Shannon Entropy $\mathbb{H}(I) = E[I(X)]$

Vocabulary

- Mutual information is defined: $I(X;Y) = \sum_{y \in Y} \sum_{x \in X} p(x,y) log\left(\frac{p(x,y)}{p(x)p(y)}\right)$
- Binomial distribution determines the probability of k successes in n trials, given a parameter Θ $p(v=k\mid\Theta)=\binom{n}{k}\Theta^k(1-\Theta)^{n-k}$
- Concentration parameters specify how concentrated the distribution is for each category
- Mutual information is defined:

$$I(X;Y) = \sum_{y \in Y} \sum_{x \in X} p(x,y) log\left(\frac{p(x,y)}{p(x)p(y)}\right)$$

Key Points

- Beta distribution to express the likelihood for the trials with binary outcomes
- Binomial distribution to model distribution of multiple trials
- Kullback-Leibler Divergence to measure the fit of a likelihood function
- Maximize model fit with K-L divergence:
- Can do Bayesian estimation of model param $\frac{1}{p \in D} \sum_{x \in D} \log q(x)$ imum a posteriori value
- Categorical and Dirichlet Distributions used for problems with multiple categories
- For Multivariate Distributions with some vector of unknown parameters, we can fit the model by independently maximizing the likelihood

Key Points

- Learning DAG structure is an unsupervised learning problem typically requiring massive amounts of data and with no marked cases
 - Algorithm: score metric (ex. Bayesian Information Criteria) + search method (ex. hill climbing) + starting point (fully connected network OR completely unconnected)
 - Ex. K2 score and K2 algorithm
 - Ex. Chow-Liu Tree Algorithm
 - Multiple random starts help